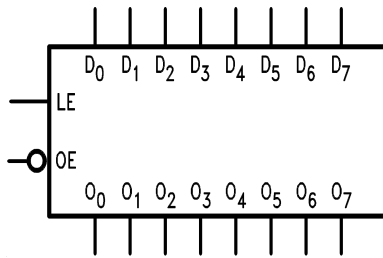
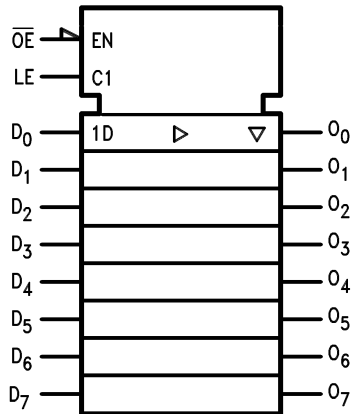


### Logic Symbol



### IEEE/IEC



### Functional Description

The ACQ/ACTQ373 contains eight D-type latches with 3-STATE standard outputs. When the Latch Enable (LE) input is HIGH, data on the  $D_n$  inputs enters the latches. In this condition the latches are transparent, i.e., a latch output will change state each time its D input changes. When LE is LOW, the latches store the information that was present on the D inputs at setup time preceding the HIGH-to-LOW transition of LE. The 3-STATE standard outputs are controlled by the Output Enable ( $\overline{OE}$ ) input. When  $\overline{OE}$  is LOW, the standard outputs are in the 2-state mode. When  $\overline{OE}$  is HIGH, the standard outputs are in the high impedance mode but this does not interfere with entering new data into the latches.

### Truth Table

Inputs			Outputs
LE	$\overline{OE}$	$D_n$	$O_n$
X	H	X	Z
H	L	L	L
H	L	H	H
L	L	X	$O_0$

H = HIGH Voltage Level

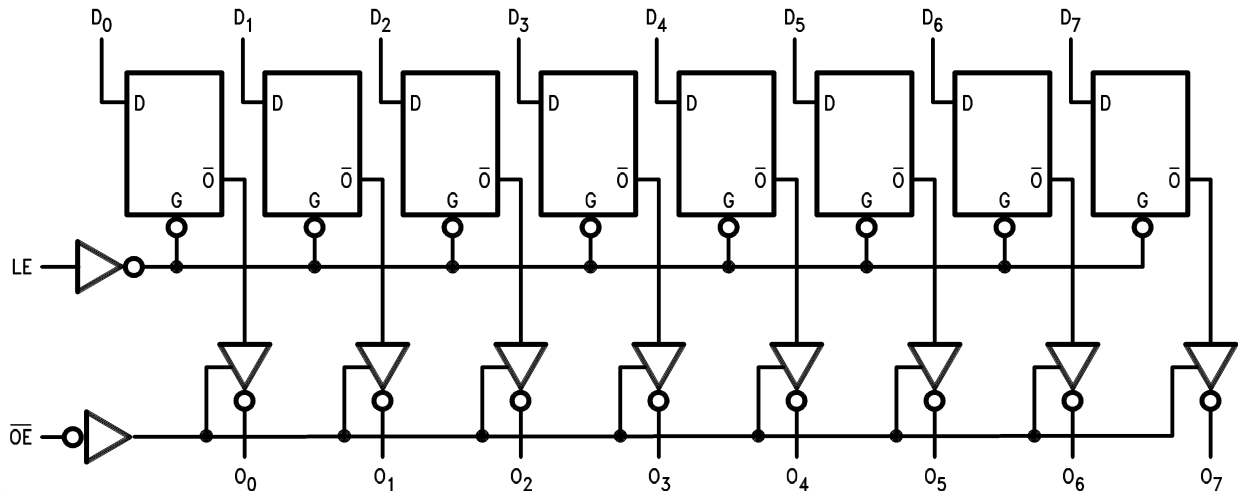
L = LOW Voltage Level

Z = High Impedance

X = Immaterial

$O_0$  = Previous  $O_0$  before HIGH-to-LOW transition of Latch Enable

**Logic Diagram**



Please note that this diagram is provided only for the understanding of logic operations and should not be used to estimate propagation delays.

## Absolute Maximum Ratings

Stresses exceeding the absolute maximum ratings may damage the device. The device may not function or be operable above the recommended operating conditions and stressing the parts to these levels is not recommended. In addition, extended exposure to stresses above the recommended operating conditions may affect device reliability. The absolute maximum ratings are stress ratings only.

Symbol	Parameter	Rating
$V_{CC}$	Supply Voltage	-0.5V to +7.0V
$I_{IK}$	DC Input Diode Current	
	$V_I = -0.5V$	-20mA
	$V_I = V_{CC} + 0.5V$	+20mA
$V_I$	DC Input Voltage	-0.5V to $V_{CC} + 0.5V$
$I_{OK}$	DC Output Diode Current	
	$V_O = -0.5V$	-20mA
	$V_O = V_{CC} + 0.5V$	+20mA
$V_O$	DC Output Voltage	-0.5V to $V_{CC} + 0.5V$
$I_O$	DC Output Source or Sink Current	$\pm 50mA$
$I_{CC}$ or $I_{GND}$	DC $V_{CC}$ or Ground Current per Output Pin	$\pm 50mA$
$T_{STG}$	Storage Temperature	-65°C to +150°C
	DC Latch-Up Source or Sink Current	$\pm 300mA$
$T_J$	Junction Temperature	140°C

## Recommended Operating Conditions

The Recommended Operating Conditions table defines the conditions for actual device operation. Recommended operating conditions are specified to ensure optimal performance to the datasheet specifications. Fairchild does not recommend exceeding them or designing to absolute maximum ratings.

Symbol	Parameter	Rating
$V_{CC}$	Supply Voltage	
	ACQ	2.0V to 6.0V
	ACTQ	4.5V to 5.5V
$V_I$	Input Voltage	0V to $V_{CC}$
$V_O$	Output Voltage	0V to $V_{CC}$
$T_A$	Operating Temperature	-40°C to +85°C
$\Delta V / \Delta t$	Minimum Input Edge Rate, ACQ Devices: $V_{IN}$ from 30% to 70% of $V_{CC}$ , $V_{CC}$ @ 3.0V, 4.5V, 5.5V	125mV/ns
$\Delta V / \Delta t$	Minimum Input Edge Rate, ACTQ Devices: $V_{IN}$ from 0.8V to 2.0V, $V_{CC}$ @ 4.5V, 5.5V	125mV/ns

## DC Electrical Characteristics for ACQ

Symbol	Parameter	V <sub>CC</sub> (V)	Conditions	T <sub>A</sub> = +25°C		T <sub>A</sub> = -40°C to +85°C		Units	
				Typ.	Guaranteed Limits				
V <sub>IH</sub>	Minimum HIGH Level Input Voltage	3.0	V <sub>OUT</sub> = 0.1V or V <sub>CC</sub> - 0.1V	1.5	2.1	2.1		V	
		4.5		2.25	3.15	3.15			
		5.5		2.75	3.85	3.85			
V <sub>IL</sub>	Maximum LOW Level Input Voltage	3.0	V <sub>OUT</sub> = 0.1V or V <sub>CC</sub> - 0.1V	1.5	0.9	0.9		V	
		4.5		2.25	1.35	1.35			
		5.5		2.75	1.65	1.65			
V <sub>OH</sub>	Minimum HIGH Level Output Voltage	3.0	I <sub>OUT</sub> = -50μA	2.99	2.9	2.9		V	
		4.5		4.49	4.4	4.4			
		5.5		5.49	5.4	5.4			
		3.0	V <sub>IN</sub> = V <sub>IL</sub> or V <sub>IH</sub> ; I <sub>OH</sub> = -12mA			2.56	2.46		
		4.5	I <sub>OH</sub> = -24mA			3.86	3.76		
		5.5	I <sub>OH</sub> = -24mA <sup>(1)</sup>			4.86	4.76		
V <sub>OL</sub>	Maximum LOW Level Output Voltage	3.0	I <sub>OUT</sub> = 50μA	0.002	0.1	0.1		V	
		4.5		0.001	0.1	0.1			
		5.5		0.001	0.1	0.1			
		3.0	V <sub>IN</sub> = V <sub>IL</sub> or V <sub>IH</sub> ; I <sub>OL</sub> = 12 mA			0.36	0.44		
		4.5	I <sub>OL</sub> = 24 mA			0.36	0.44		
		5.5	I <sub>OL</sub> = 24 mA <sup>(1)</sup>			0.36	0.44		
I <sub>IN</sub> <sup>(3)</sup>	Maximum Input Leakage Current	5.5	V <sub>I</sub> = V <sub>CC</sub> , GND		±0.1	±1.0		μA	
I <sub>OLD</sub>	Minimum Dynamic Output Current <sup>(2)</sup>	5.5	V <sub>OLD</sub> = 1.65V Max.			75		mA	
I <sub>OHD</sub>		5.5	V <sub>OHD</sub> = 3.85V Min.			-75		mA	
I <sub>CC</sub> <sup>(3)</sup>	Maximum Quiescent Supply Current	5.5	V <sub>IN</sub> = V <sub>CC</sub> or GND		4.0	40.0		μA	
I <sub>OZ</sub>	Maximum 3-STATE Leakage Current	5.5	V <sub>I</sub> (OE) = V <sub>IL</sub> , V <sub>IH</sub> ; V <sub>I</sub> = V <sub>CC</sub> , GND; V <sub>O</sub> = V <sub>CC</sub> , GND		±0.25	±2.5		μA	
V <sub>OLP</sub>	Quiet Output Maximum Dynamic V <sub>OL</sub>	5.0	Figures 1 & 2 <sup>(4)</sup>	1.1	1.5			V	
V <sub>OLV</sub>	Quiet Output Maximum Dynamic V <sub>OL</sub>	5.0	Figures 1 & 2 <sup>(4)</sup>	-0.6	-1.2			V	
V <sub>IHD</sub>	Minimum HIGH Level Dynamic Input Voltage	5.0	<sup>(5)</sup>	3.1	3.5			V	
V <sub>ILD</sub>	Maximum LOW Level Dynamic Input Voltage	5.0	<sup>(5)</sup>	1.9	1.5			V	

**Notes:**

- All outputs loaded; thresholds on input associated with output under test.
- Maximum test duration 2.0ms, one output loaded at a time.
- I<sub>IN</sub> and I<sub>CC</sub> @ 3.0V are guaranteed to be less than or equal to the respective limit @ 5.5V V<sub>CC</sub>.
- Max number of outputs defined as (n). Data inputs are driven 0V to 5V. One output @ GND.
- Max number of data inputs (n) switching. (n-1) inputs switching 0V to 5V (ACQ). Input-under-test switching: 5V to threshold (V<sub>ILD</sub>), 0V to threshold (V<sub>IHD</sub>), f = 1MHz.

## DC Electrical Characteristics for ACTQ

Symbol	Parameter	V <sub>CC</sub> (V)	Conditions	T <sub>A</sub> = +25°C		T <sub>A</sub> = -40°C to +85°C		Units
				Typ.	Guaranteed Limits			
V <sub>IH</sub>	Minimum HIGH Level Input Voltage	4.5	V <sub>OUT</sub> = 0.1V or V <sub>CC</sub> - 0.1V	1.5	2.0	2.0		V
		5.5		1.5	2.0	2.0		
V <sub>IL</sub>	Maximum LOW Level Input Voltage	4.5	V <sub>OUT</sub> = 0.1V or V <sub>CC</sub> - 0.1V	1.5	0.8	0.8		V
		5.5		1.5	0.8	0.8		
V <sub>OH</sub>	Minimum HIGH Level Output Voltage	4.5	I <sub>OUT</sub> = -50μA	4.49	4.4	4.4		V
		5.5		5.49	5.4	5.4		
		4.5	V <sub>IN</sub> = V <sub>IL</sub> or V <sub>IH</sub> : I <sub>OH</sub> = -24mA			3.86	3.76	
		5.5	I <sub>OH</sub> = -24mA <sup>(6)</sup>			4.86	4.76	
V <sub>OL</sub>	Maximum LOW Level Output Voltage	4.5	I <sub>OUT</sub> = 50μA	0.001	0.1	0.1		V
		5.5		0.001	0.1	0.1		
		4.5	V <sub>IN</sub> = V <sub>IL</sub> or V <sub>IH</sub> : I <sub>OL</sub> = 24 mA			0.36	0.44	
		5.5	I <sub>OL</sub> = 24 mA <sup>(6)</sup>			0.36	0.44	
I <sub>IN</sub> <sup>(3)</sup>	Maximum Input Leakage Current	5.5	V <sub>I</sub> = V <sub>CC</sub> , GND		±0.1	±1.0		μA
I <sub>OZ</sub>	Maximum 3-STATE Leakage Current	5.5	V <sub>I</sub> = V <sub>IL</sub> , V <sub>IH</sub> , V <sub>O</sub> = V <sub>CC</sub> , GND		±0.25	±2.5		μA
I <sub>CCCT</sub>	Maximum I <sub>CC</sub> /Input	5.5	V <sub>I</sub> = V <sub>CC</sub> - 2.1V	0.6		1.5		mA
I <sub>OLD</sub>	Minimum Dynamic Output Current <sup>(7)</sup>	5.5	V <sub>OLD</sub> = 1.65V Max.			75		mA
I <sub>OHD</sub>		5.5	V <sub>OHD</sub> = 3.85V Min.			-75		mA
I <sub>CC</sub> <sup>(3)</sup>	Maximum Quiescent Supply Current	5.5	V <sub>IN</sub> = V <sub>CC</sub> , or GND		4.0	40.0		μA
V <sub>OLP</sub>	Quiet Output Maximum Dynamic V <sub>OL</sub>	5.0	Figures 1 & 2 <sup>(8)</sup>	1.1	1.5			V
V <sub>OLV</sub>	Quiet Output Minimum Dynamic V <sub>OL</sub>	5.0	Figures 1 & 2 <sup>(8)</sup>	-0.6	-1.2			V
V <sub>IHD</sub>	Minimum HIGH Level Dynamic Input Voltage	5.0	<sup>(9)</sup>	1.9	2.2			V
V <sub>ILD</sub>	Maximum LOW Level Dynamic Input Voltage	5.0	<sup>(9)</sup>	1.2	0.8			V

**Notes:**

- All outputs loaded; thresholds on input associated with output under test.
- Maximum test duration 2.0ms, one output loaded at a time.
- Max number of outputs defined as (n). Data inputs are driven 0V to 3V. One output @ GND.
- Max number of data inputs (n) switching. (n-1) inputs switching 0V to 3V (ACTQ). Input-under-test switching: 3V to threshold (V<sub>ILD</sub>), 0V to threshold (V<sub>IHD</sub>), f = 1 MHz.

## AC Electrical Characteristics for ACQ

Symbol	Parameter	V <sub>CC</sub> (V) <sup>(10)</sup>	T <sub>A</sub> = +25°C, C <sub>L</sub> = 50pF			T <sub>A</sub> = -40°C to +85°C, C <sub>L</sub> = 50pF		Units
			Min.	Typ.	Max.	Min.	Max.	
t <sub>PHL</sub> , t <sub>PLH</sub>	Propagation Delay, D <sub>n</sub> to O <sub>n</sub>	3.3	2.5	8.0	10.5	2.5	11.0	ns
		5.0	1.5	5.5	7.0	1.5	7.5	
t <sub>PHL</sub> , t <sub>PLH</sub>	Propagation Delay, LE to O <sub>n</sub>	3.3	2.5	8.0	12.0	2.5	12.5	ns
		5.0	2.0	6.0	8.0	2.0	8.5	
t <sub>PZL</sub> , t <sub>PZH</sub>	Output Enable Time	3.3	2.5	8.5	13.0	2.5	13.5	ns
		5.0	1.5	6.5	8.5	1.5	9.0	
t <sub>PHZ</sub> , t <sub>PLZ</sub>	Output Disable Time	3.3	1.0	9.0	14.5	1.0	15.0	ns
		5.0	1.0	6.5	9.5	1.0	10.0	
t <sub>OSSL</sub> , t <sub>OSLH</sub>	Output to Output Skew, D <sub>n</sub> to O <sub>n</sub> <sup>(11)</sup>	3.3		1.0	1.5		1.5	ns
		5.0		0.5	1.0		1.0	

**Note:**

10. Voltage range 5.0 is 5.0V ± 0.5V. Voltage range 3.3 is 3.3V ± 0.3V.

11. Skew is defined as the absolute value of the difference between the actual propagation delay for any two separate outputs of the same device. The specification applies to any outputs switching in the same direction, either HIGH-to-LOW (t<sub>OSSL</sub>) or LOW-to-HIGH (t<sub>OSLH</sub>). Parameter guaranteed by design.

## AC Operating Requirements for ACQ

Symbol	Parameter	V <sub>CC</sub> (V) <sup>(12)</sup>	T <sub>A</sub> = +25°C, C <sub>L</sub> = 50pF		T <sub>A</sub> = -40°C to +85°C, C <sub>L</sub> = 50 pF		Units
			Typ.	Guaranteed Minimum			
t <sub>S</sub>	Setup Time, HIGH or LOW, D <sub>n</sub> to LE	3.3	0	3.0	3.0		ns
		5.0	0	3.0	3.0		
t <sub>H</sub>	Hold Time, HIGH or LOW, D <sub>n</sub> to LE	3.3	0	1.5	1.5		ns
		5.0	0	1.5	1.5		
t <sub>W</sub>	LE Pulse Width, HIGH	3.3	2.0	4.0	4.0		ns
		5.0	2.0	4.0	4.0		

**Note:**

12. Voltage range 5.0 is 5.0V ± 0.5V. Voltage range 3.3 is 3.3V ± 0.3V.

**AC Electrical Characteristics for ACTQ**

Symbol	Parameter	V <sub>CC</sub> (V) <sup>(13)</sup>	T <sub>A</sub> = +25°C, C <sub>L</sub> = 50pF			T <sub>A</sub> = -40°C to +85°C, C <sub>L</sub> = 50pF		Units
			Min.	Typ.	Max.	Min.	Max.	
t <sub>PHL</sub> , t <sub>PLH</sub>	Propagation Delay, D <sub>n</sub> to O <sub>n</sub>	5.0	2.0	6.5	7.5	2.0	8.0	ns
t <sub>PHL</sub> , t <sub>PLH</sub>	Propagation Delay, LE to O <sub>n</sub>	5.0	2.5	7.0	8.5	2.5	9.0	ns
t <sub>PZL</sub> , t <sub>PZH</sub>	Output Enable Time	5.0	2.0	7.0	9.0	2.0	9.5	ns
t <sub>PHZ</sub> , t <sub>PLZ</sub>	Output Disable Time	5.0	1.0	8.0	10.0	1.0	10.5	ns
t <sub>OSHL</sub> , t <sub>OSLH</sub>	Output to Output Skew, D <sub>n</sub> to O <sub>n</sub> <sup>(14)</sup>	5.0		0.5	1.0		1.0	ns

**Notes:**

13. Voltage range 5.0 is 5.0V ± 0.5V.

14. Skew is defined as the absolute value of the difference between the actual propagation delay for any two separate outputs of the same device. The specification applies to any outputs switching in the same direction, either HIGH-to-LOW (t<sub>OSHL</sub>) or LOW-to-HIGH (t<sub>OSLH</sub>). Parameter guaranteed by design.

**AC Operating Requirements for ACTQ**

Symbol	Parameter	V <sub>CC</sub> (V) <sup>(15)</sup>	T <sub>A</sub> = +25°C, C <sub>L</sub> = 50pF		T <sub>A</sub> = -40°C to +85°C, C <sub>L</sub> = 50 pF		Units
			Typ.	Guaranteed Minimum			
t <sub>S</sub>	Setup Time, HIGH or LOW, D <sub>n</sub> to LE	5.0	0	3.0	3.0		ns
t <sub>H</sub>	Hold Time, HIGH or LOW, D <sub>n</sub> to LE	5.0	0	1.5	1.5		ns
t <sub>W</sub>	LE Pulse Width, HIGH	5.0	2.0	4.0	4.0		ns

**Note:**

15. Voltage range 5.0 is 5.0V ± 0.5V

**Capacitance**

Symbol	Parameter	Conditions	Typ.	Units
C <sub>IN</sub>	Input Capacitance	V <sub>CC</sub> = OPEN	4.5	pF
C <sub>PD</sub>	Power Dissipation Capacitance	V <sub>CC</sub> = 5.0V	44.0	pF

## FACT Noise Characteristics

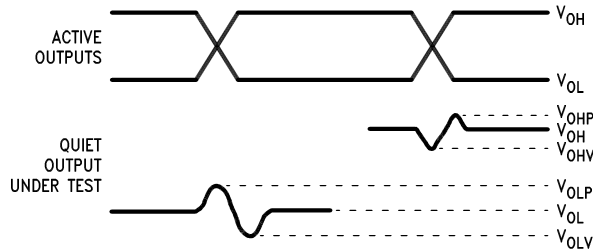
The setup of a noise characteristics measurement is critical to the accuracy and repeatability of the tests. The following is a brief description of the setup used to measure the noise characteristics of FACT.

### Equipment:

- Hewlett Packard Model 8180A Word Generator
- PC-163A Test Fixture
- Tektronics Model 7854 Oscilloscope

### Procedure:

1. Verify Test Fixture Loading: Standard Load 50pF, 500Ω.
2. Deskew the HFS generator so that no two channels have greater than 150ps skew between them. This requires that the oscilloscope be deskewed first. It is important to deskew the HFS generator channels before testing. This will ensure that the outputs switch simultaneously.
3. Terminate all inputs and outputs to ensure proper loading of the outputs and that the input levels are at the correct voltage.
4. Set the HFS generator to toggle all but one output at a frequency of 1MHz. Greater frequencies will increase DUT heating and effect the results of the measurement.
5. Set the HFS generator input levels at 0V LOW and 3V HIGH for ACT devices and 0V LOW and 5V HIGH for AC devices. Verify levels with an oscilloscope.



### Notes:

16.  $V_{OHV}$  and  $V_{OLP}$  are measured with respect to ground reference.
17. Input pulses have the following characteristics:  
 $f = 1\text{MHz}$ ,  $t_r = 3\text{ns}$ ,  $t_f = 3\text{ns}$ , skew < 150ps.

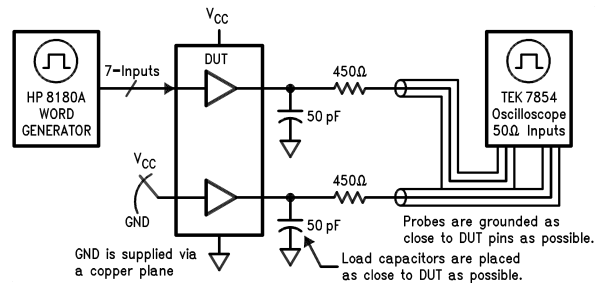
**Figure 1. Quiet Output Noise Voltage Waveforms**

### $V_{OLP}/V_{OLV}$ and $V_{OHP}/V_{OHV}$ :

- Determine the quiet output pin that demonstrates the greatest noise levels. The worst case pin will usually be the furthest from the ground pin. Monitor the output voltages using a 50Ω coaxial cable plugged into a standard SMB type connector on the test fixture. Do not use an active FET probe.
- Measure  $V_{OLP}$  and  $V_{OLV}$  on the quiet output during the worst case transition for active and enable. Measure  $V_{OHP}$  and  $V_{OHV}$  on the quiet output during the worst case active and enable transition.
- Verify that the GND reference recorded on the oscilloscope has not drifted to ensure the accuracy and repeatability of the measurements.

### $V_{ILD}$ and $V_{IHD}$ :

- Monitor one of the switching outputs using a 50Ω coaxial cable plugged into a standard SMB type connector on the test fixture. Do not use an active FET probe.
- First increase the input LOW voltage level,  $V_{IL}$ , until the output begins to oscillate or steps out a min of 2ns. Oscillation is defined as noise on the output LOW level that exceeds  $V_{IL}$  limits, or on output HIGH levels that exceed  $V_{IH}$  limits. The input LOW voltage level at which oscillation occurs is defined as  $V_{ILD}$ .
- Next decrease the input HIGH voltage level,  $V_{IH}$  until the output begins to oscillate or steps out a min of 2ns. Oscillation is defined as noise on the output LOW level that exceeds  $V_{IL}$  limits, or on output HIGH levels that exceed  $V_{IH}$  limits. The input HIGH voltage level at which oscillation occurs is defined as  $V_{IHD}$ .
- Verify that the GND reference recorded on the oscilloscope has not drifted to ensure the accuracy and repeatability of the measurements.



**Figure 2. Simultaneous Switching Test Circuit**



### Physical Dimensions

Dimensions are in inches (millimeters) unless otherwise noted.

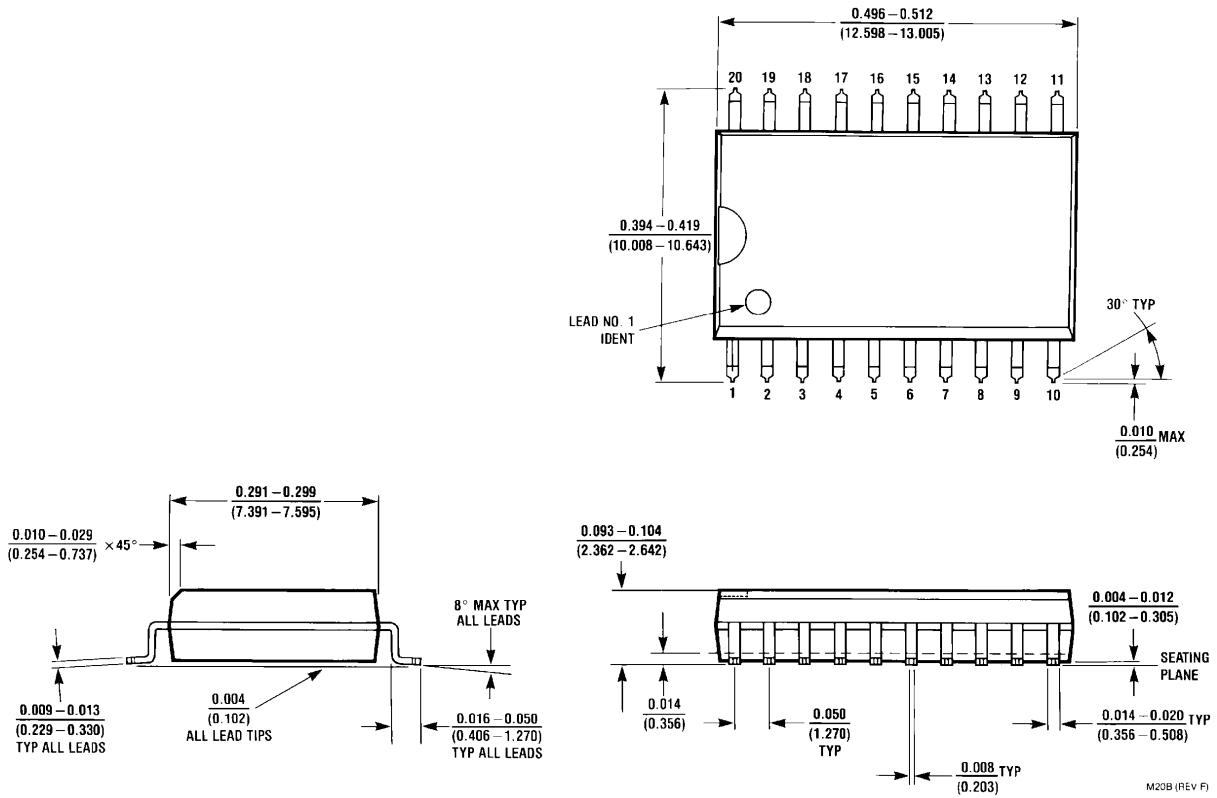
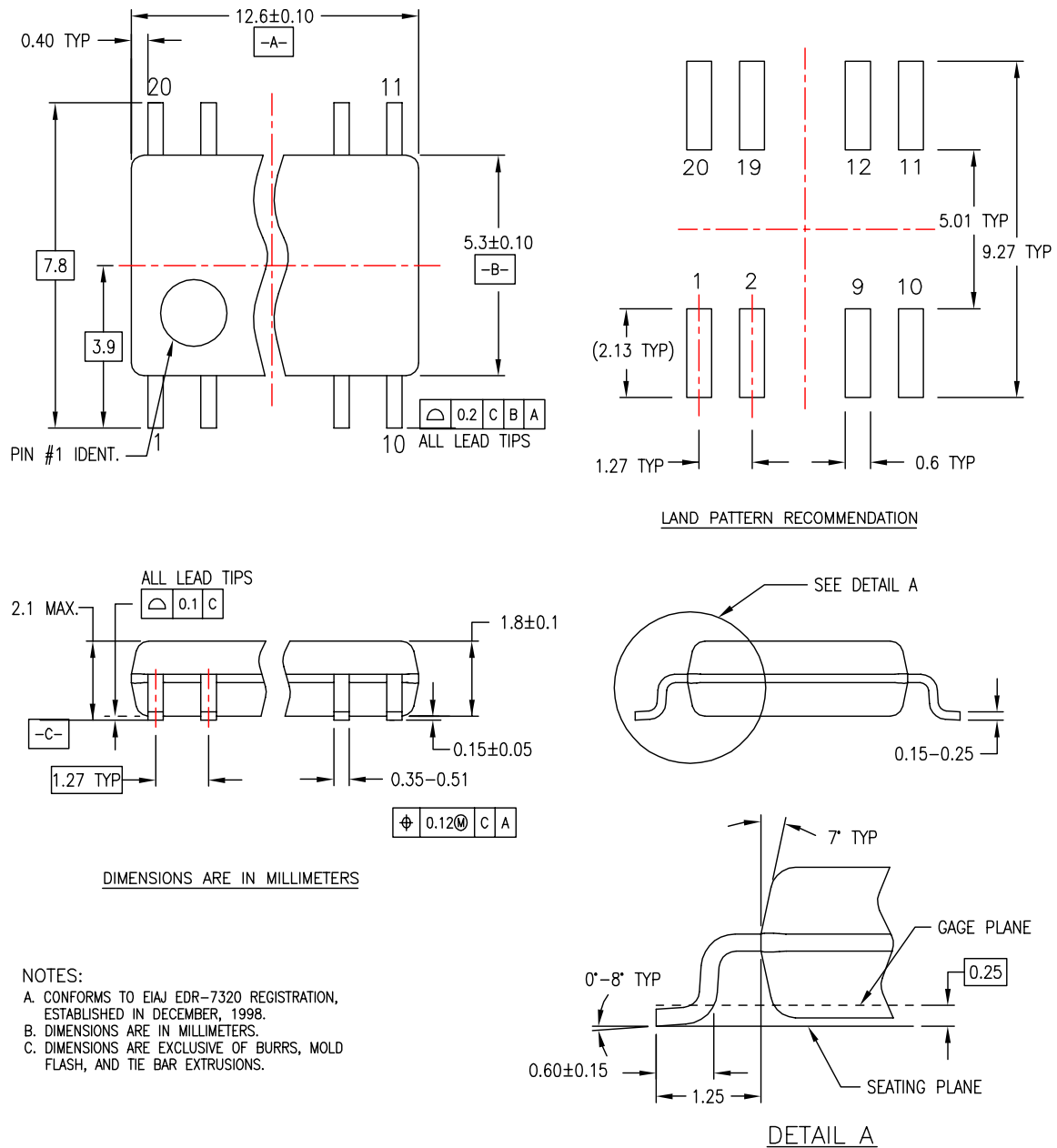


Figure 3. 20-Lead Small Outline Integrated Circuit (SOIC), JEDEC MS-013, 0.300" Wide Package Number M20B

**Physical Dimensions** (Continued)

Dimensions are in millimeters unless otherwise noted.



M20DREVC


**Figure 4. 20-Lead Small Outline Package (SOP), EIAJ TYPE II, 5.3mm Wide Package Number M20D**





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Across the board. Around the world. <sup>™</sup>	<i>i-Lo</i> <sup>™</sup>	QFET <sup>®</sup>	TINYOPTO <sup>™</sup>
ActiveArray <sup>™</sup>	ImpliedDisconnect <sup>™</sup>	QS <sup>™</sup>	TinyPower <sup>™</sup>
Bottomless <sup>™</sup>	IntelliMAX <sup>™</sup>	QT Optoelectronics <sup>™</sup>	TinyWire <sup>™</sup>
Build it Now <sup>™</sup>	ISOPLANAR <sup>™</sup>	Quiet Series <sup>™</sup>	TruTranslation <sup>™</sup>
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CROSSVOLT <sup>™</sup>	MicroPak <sup>™</sup>	RapidConnect <sup>™</sup>	UHC <sup>®</sup>
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Current Transfer Logic <sup>™</sup>	MSX <sup>™</sup>	SMART START <sup>™</sup>	VCX <sup>™</sup>
DOME <sup>™</sup>	MSXPro <sup>™</sup>	SPM <sup>®</sup>	Wire <sup>™</sup>
E <sup>2</sup> CMOS <sup>™</sup>	OCX <sup>™</sup>	STEALTH <sup>™</sup>	
EcoSPARK <sup>®</sup>	OCXPro <sup>™</sup>	SuperFET <sup>™</sup>	
EnSigna <sup>™</sup>	OPTOLOGIC <sup>®</sup>	SuperSOT <sup>™</sup> -3	
FACT Quiet Series <sup>™</sup>	OPTOPLANAR <sup>®</sup>	SuperSOT <sup>™</sup> -6	
FACT <sup>®</sup>	PACMAN <sup>™</sup>	SuperSOT <sup>™</sup> -8	
FAST <sup>®</sup>	POP <sup>™</sup>	SyncFET <sup>™</sup>	
FASTr <sup>™</sup>	Power220 <sup>®</sup>	TCM <sup>™</sup>	
FPS <sup>™</sup>	Power247 <sup>®</sup>	The Power Franchise <sup>®</sup>	
FRFET <sup>®</sup>	PowerEdge <sup>™</sup>	 ™	
GlobalOptoisolator <sup>™</sup>	PowerSaver <sup>™</sup>	TinyBoost <sup>™</sup>	
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## PRODUCT STATUS DEFINITIONS

### Definition of Terms

Datasheet Identification	Product Status	Definition
Advance Information	Formative or In Design	This datasheet contains the design specifications for product development. Specifications may change in any manner without notice.
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